Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/618,800	MILLS ET AL.	
Examiner	Art Unit	
J. Derek Rutten	2192	

SEARCHED						
Class	Subclass	Date	Examiner			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Name Search PLUS search STIC database search	11/29/2006	JDR		
717/107,163; 70019,275 Text search only See search history printout	11/29/2006	JDR		
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	11/29/2006	JDR		
717/107,163; 70019,275 Text search only See search history printout	11/30/2006	JDR		
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IEEE - ieeexplore.ieee.org See search history printout	12/1/2006	JDR		
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